



BYD Microelectronics Co., Ltd

BF9024SPD-M

P-Channel MOSFET and Schottky Diode

General Description

The BF9024SPD-M uses advanced trench technology to provide excellent $R_{DS(on)}$ and low gate charge. This device is suitable for used as a load switch or in PWM applications.

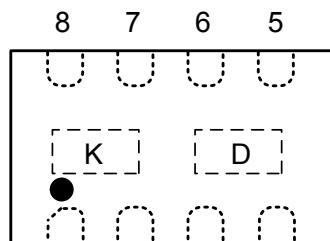
Features

MOSFET

- V_{DS} (V) = -20V
- I_D = -2.7A
- Low on-state resistance
 $R_{DS(on)} < 90m\Omega$. ($V_{GS} = -4.5V$)
 $R_{DS(on)} < 120m\Omega$. ($V_{GS} = -2.5V$)

Schottky Diode

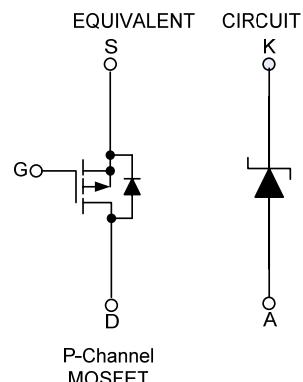
- $V_F=0.42V$



1,2 Anode; 3 Source; 4 Gate
 5,6 Drain; 7,8 Cathode
 K: Cathode; D: Drain

Absolute Maximum Ratings (Ta = 25°C)

Parameter	Symbol	Ratings	Unit
Mosfet			
Drain to Source Voltage (MOSFET and Schottky)	V_{DSS}	-20	V
Gate to Source Voltage	V_{GSS}	± 8	V
Drain Current (DC)	$I_{D(DC)}$	-2.7	A
Drain Current (pulse)	$I_{D(pulse)}$	-10	A
Maximun Power Dissipation ^a	P_D	1.1	W
Channel Temperature	T_{ch}	150	°C
Storage Temperature	T_{stg}	-55~+150	°C
Schottky Diode			
Reverse Voltage	V_{KA}	20	V
Average Forward Current	I_F	1	A
Pulsed Forward Current	I_{FM}	7	A
Maximun Power Dissipation ^a	P_D	0.96	W
Storage Temperature	T_{stg}	-55~+150	°C



Note a. Mounted on FR4 Board of 1"x1".

Caution: These values must not be exceeded under any conditions.

Ordering Information

- BF9024SPD-M
- DFNWB3*1.8-8L

**Electrical Characteristics ($T_C = 25^\circ\text{C}$)**

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Mosfet						
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -20\text{V}, V_{GS} = 0\text{V}$	—	—	-1	μA
Gate Leakage Current	I_{GSS}	$V_{GS} = \pm 8\text{V}, V_{DS} = 0\text{V}$	—	—	± 100	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -0.25\text{mA}$	-0.45	—	-1	V
Forward Transfer Admittance	$ y_{fs} $	$V_{DS} = -10\text{V}, I_D = -2\text{A}$	—	7	—	S
Drain to Source On-state Resistance	$R_{DS(\text{on})}$	$V_{GS} = -4.5\text{V}, I_D = -2\text{A}$	—	73	90	$\text{m}\Omega$
		$V_{GS} = -2.5\text{V}, I_D = -2\text{A}$	—	99	120	$\text{m}\Omega$
Input Capacitance	C_{iss}	$V_{DS} = -10\text{V}, V_{GS} = 0, f = 1\text{MHz}$	—	427	—	pF
Output Capacitance	C_{oss}		—	72	—	pF
Reverse Transfer Capacitance	C_{rss}		—	50	—	pF
Turn-on Delay Time	$t_{d(on)}$	$V_{DS} = -10\text{V}, I_D = -1\text{A}, V_{GS} = -4.5\text{V}, R_G = 6\Omega$	—	15	—	ns
Rise Time	t_r		—	36	—	ns
Turn-off Delay Time	$t_{d(off)}$		—	36	—	ns
Fall Time	t_f		—	30	—	ns
Total Gate Charge	Q_G	$V_{DS} = -10\text{V}, V_{GS} = -4.5\text{V}, I_D = -2\text{A}$	—	5	—	nC
Gate to Source Charge	Q_{GS}		—	1.5	—	nC
Gate to Drain Charge	Q_{GD}		—	1	—	nC
Body Diode Forward Voltage	$V_{F(S-D)}$	$I_F = -0.9\text{A}, V_{GS} = 0\text{V}$	—	-0.8	-1.2	V
Schottky Diode						
Forward Voltage Drop	V_F	$I_F = 0.5\text{A}$	—	0.42	0.48	V
Maximum Reverse Leakage Current	I_{rm}	$V_r = 20\text{V}$	—	0.002	0.1	mA
Junction Capacitance	C_T	$V_r = 10\text{V}$	—	35	—	pF

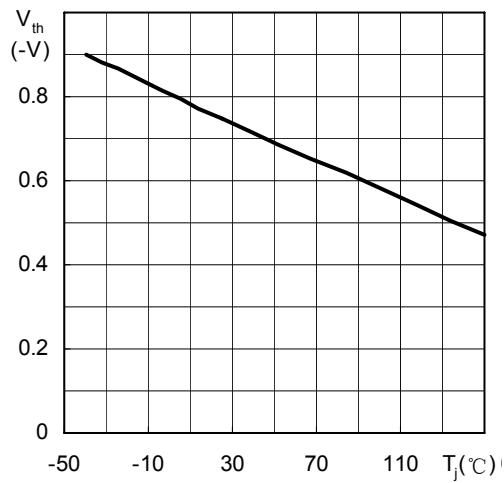
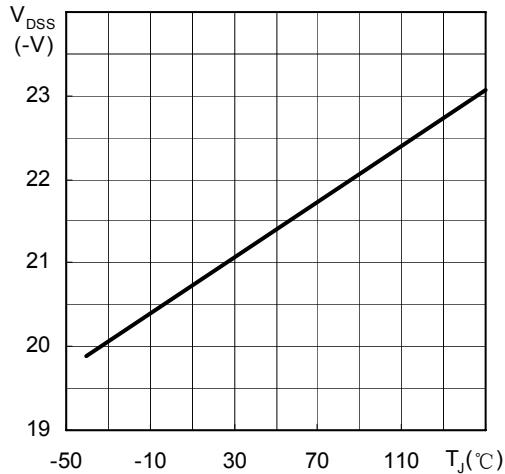
Typical characteristics (25°C unless noted)**MOSFET****Figure 1 Threshold Voltage vs. Temperature****Figure 2 V_{DSS} vs. Temperature**

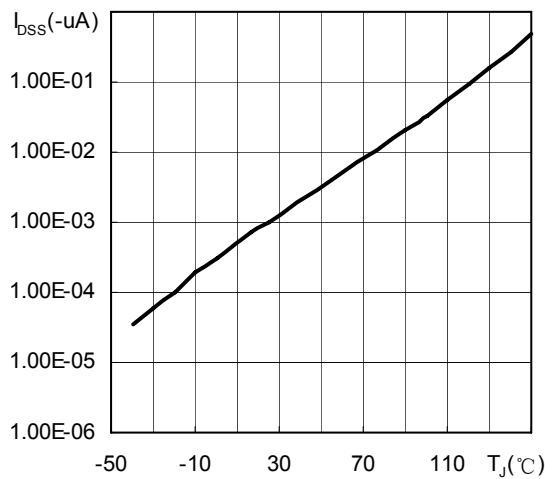
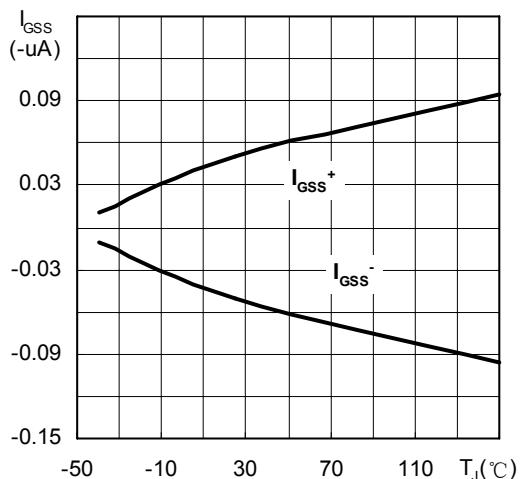
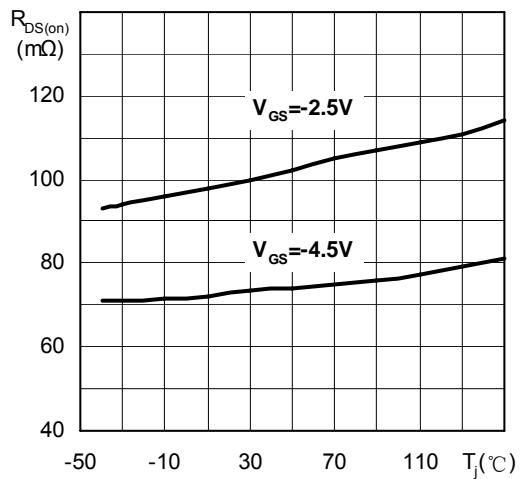
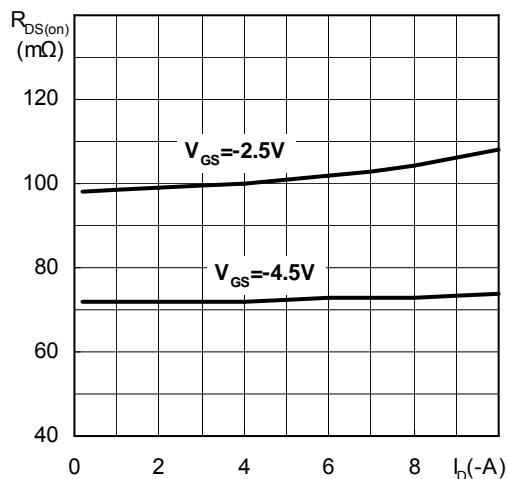
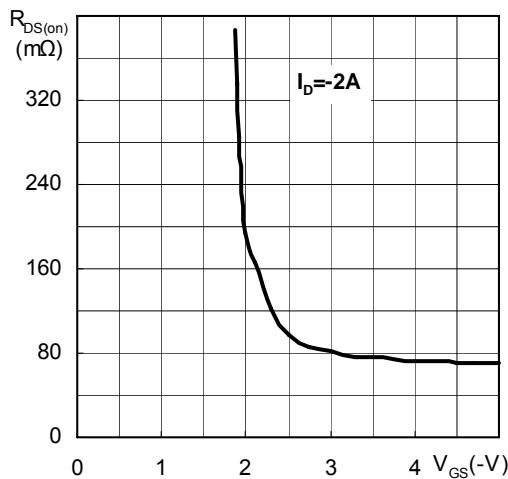
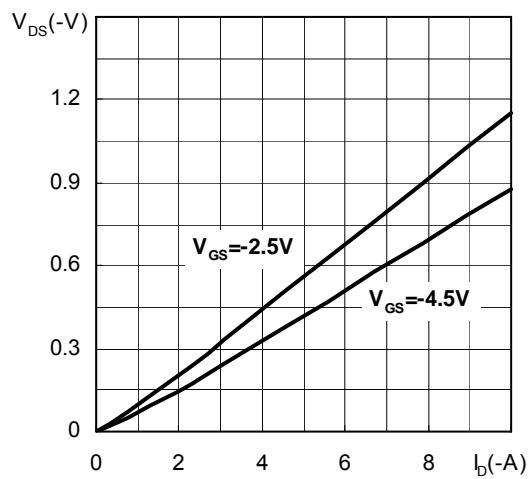
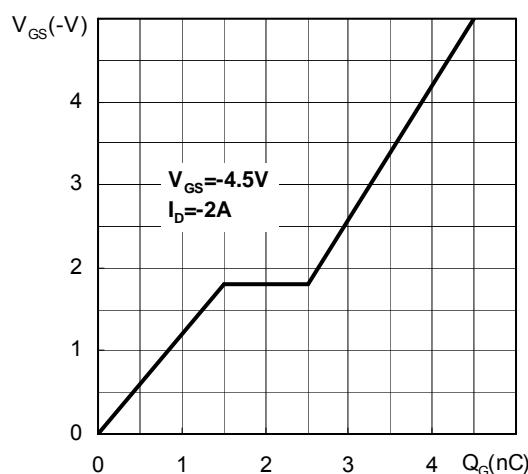
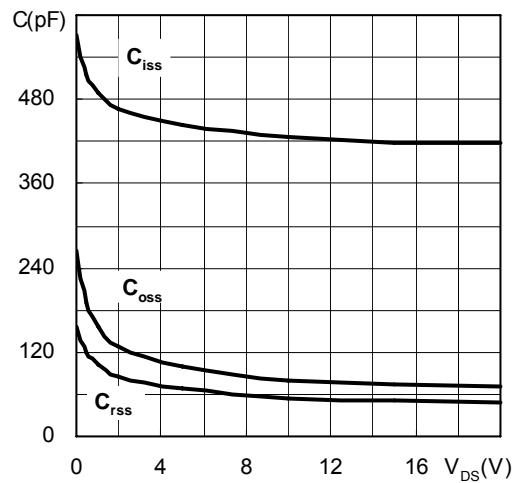
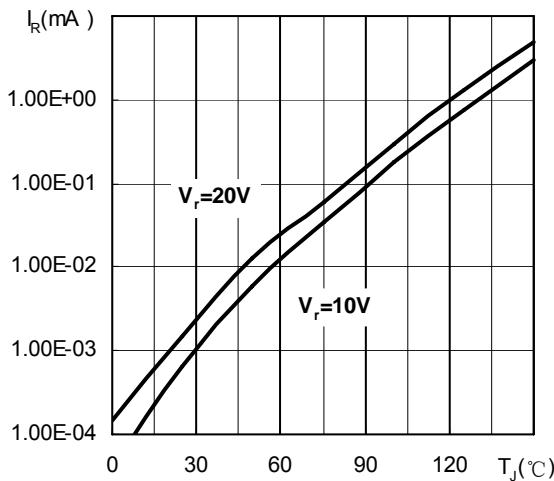
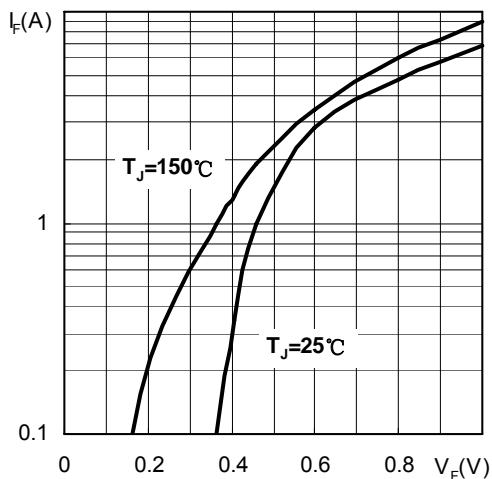
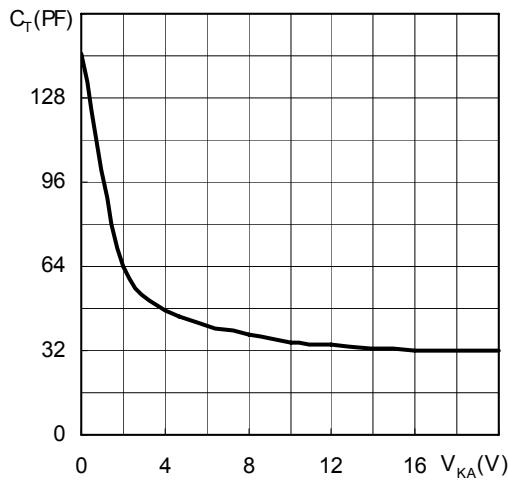
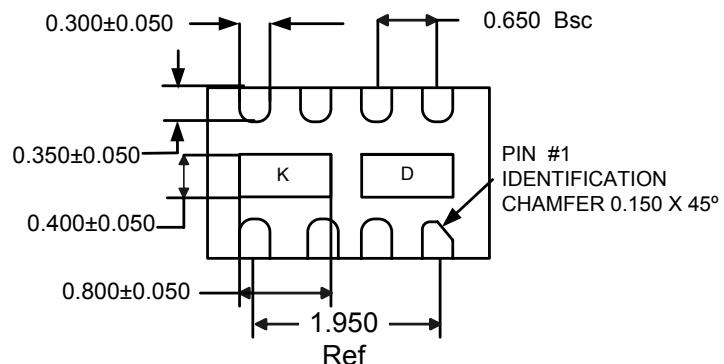
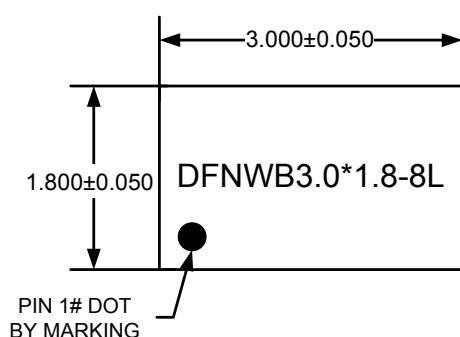
Figure 3 I_{DSS} vs. Temperature**Figure 4** I_{GSS} vs. Temperature**Figure 5** On-Resistance vs. Temperature**Figure 6** On-Resistance vs. Drain Current**Figure 7** On-Resistance
vs. Gate-to-Source Voltage**Figure 8** Drain to Source Voltage
vs. Drain Current

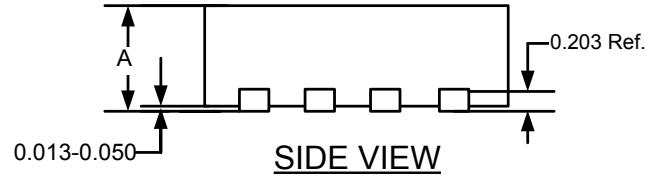
Figure 9 Gate Charge

Figure 10 Capacitance

Typical characteristics (25°C unless noted)
Schottky Diode
**Figure 11 Reverse Current
vs. Junction Temperature**

Figure 12 Forward Voltage Diode

Figure 13 Capacitance




Package Drawing

TOP VIEWBOTTOM VIEW

UNIT:MM		
A	MAX	0.800
	NDM	0.750
	MIN	0.700

**NOTE:**

- 1) Lead Plating Thickness: 0-0.050mm.
- 2) Package body sizes exclude mold flash, protrusion or gate burrs.
Mold flash, protrusion or gate burrs shall not exceed 0.10mm per side.
- 3) The size of the zone "D" is the same as the "K".



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